IN THE SPECIFICATION:

The specification has been amended as follows:

Page 9, Lines 14-19:

--Preferably, if the above-mentioned broad area is all the entire area of the specimen, the specimen spectrum can be specified more steadily. In addition, if a diameter of the above-mentioned broad area is set as not less than 100 times of the spot size of the electron beam, the specimen spectrum can be specified with accuracy.--

Page 11, Lines 7-14:

--More concretely, the arrangement is represented by <u>in</u> that each of a position of the specimen spectrum and a position of the stress impressed spectrum is compensated based on the spectrum of the external light, or that each of a position of the internal stress impressed spectrum and a position of the specimen spectrum or a position of the stress impressed spectrum is compensated based on the spectrum of the external light.--

Page 25, Lines 11-20:

--In case of doping the lanthanoid on the specimen, it is preferable that at least one of the elements is selected from the above-mentioned lanthanoid series, especially a family consisting of Sm, Eu, Tb, Y, Yb, La, Er, and Gd. Since the above-mentioned Sm, Eu, Tb, Y, Yb, La, Er, and Gd are high in light emitting efficiency compared with other element of the lanthanoid series, an amount of Sm, Eu, Tb, Y, Yb, La, Er, and Gd to be doped can be lessened. As a result, it is possible to measure a stress of the specimen without changing a property of the specimen.--

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Page 49, Line 28, through Page 50, Line 2:

--Furthermore, it is preferable that the above-mentioned lanthanoid is at least one element selected from a family consisting of Sm, Eu, Tb, Y, <u>Yb,</u> La, Er, and Gd.--